

AM25LS2519

Quad Register with Two Independently Controlled Three-State Outputs

The AM25LS2519 consists of four D-type flip-flops with a buffered common clock enable. Information meeting the set-up and hold time requirements on the D inputs is transferred to the flip-flop outputs on the LOW-to-HIGH transition of the clock. Data on the Q outputs of the flip-flops is enabled at the three-state outputs when the output control (\overline{OE}) input is LOW. When the appropriate \overline{OE} input is HIGH, the outputs are in the high impedance state. Two independent sets of outputs - W and Y - are provided such that the register can simultaneously and independently drive two buses. One set of outputs contains a polarity control such that the outputs can either be inverting or non-inverting.

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - · Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
 - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

Am25LS2519

Quad Register with Two Independently Controlled Three-State Outputs

DISTINCTIVE CHARACTERISTICS

- Two sets of fully buffered three-state outputs
- Four D-type flip-flops
- Polarity control on W outputs
- Buffered common clock enable

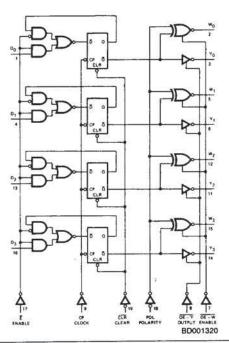
- Buffered common asynchronous clear
- Separate buffered common output enable for each set of outputs

GENERAL DESCRIPTION

The Am25LS2519 consists of four D-type flip-flops with a buffered common clock enable. Information meeting the set-up and hold time requirements on the D inputs is transferred to the flip-flop outputs on the LOW-to-HIGH transition of the clock. Data on the Q outputs of the flipflops is enabled at the three-state outputs when the output control (OE) input is LOW. When the appropriate OE input is HIGH, the outputs are in the high impedance state. Two independent sets of outputs - W and Y - are provided such that the register can simultaneously and independently drive two buses. One set of outputs contains a polarity control such that the outputs can either be inverting or noninverting.

The device also features an active LOW asynchronous clear. When the clear input is LOW, the Q output of the internal flip-flops are forced LOW independent of the other inputs. The Am25LS2519 is packaged in a space saving (0.3-inch row spacing) 20-pin package.

BLOCK DIAGRAM



RELATED PRODUCTS

Part No.	Description	
Am25S18, Am2918	Quad D Register	
Am25LS2518	Quad D Register	

03660B

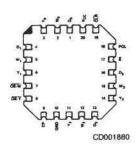


CONNECTION DIAGRAM Top View

D-20-1

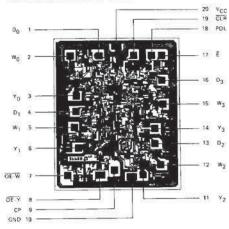
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Note: Pin 1 is marked for orientation

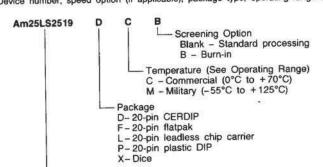
METALLIZATION AND PAD LAYOUT



DIE SIZE 0.083" x 0.099"

ORDERING INFORMATION

AMD products are available in several packages and operating ranges. The order number is formed by a combination of the following: Device number, speed option (if applicable), package type, operating range and screening option (if desired).



Device type Quad D Register

Valid Combinations PC DC, DM FM LC, LM XC, XM Am25LS2519

Valid Combinations

Consult the AMD sales office in your area to determine if a device is currently available in the combination you wish.

03660B

PIN DESCRIPTION							
Pin No.	Name	1/0	Description				
	Di	1	Any of the four D flip-flop data lines.				
17	Ē	L	Clock Enable. When LOW, the data is entered into the register on the next clock LOW-to-HIGH transition. When HIGH, the data in the register remains unchanged, regardless of the data in.				
9	CP	1	Clock Pulse. Data is entered into the register on the LOW-to-HIGH transition.				
7, 8	OE-W.	0	Output Enable. When $\overline{\text{OE}}$ is LOW, the register is enable to the output. When HIGH, the output is in the high-impedance state. The $\overline{\text{OE-W}}$ controls the W set of outputs, and $\overline{\text{OE-Y}}$ controls the Y set.				
50 x 50 x	Yi	0	Any of the four non-inverting three-state output lines.				
0.000	Wi	0	Any of the four three-state outputs with polarity control.				
18	POL	0	Polarity Control. The Wi outputs will be non-inverting when POL is LOW, and when it is HIGH, the outputs are inverting.				
19	CLR	1	Asynchronous Clear. When CLR is LOW, the internal Q flip-flops are reset to LOW.				

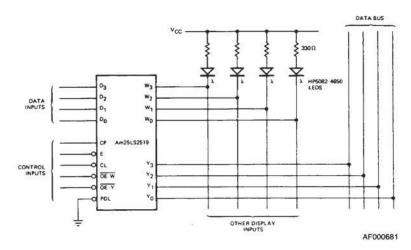
FUNCTION TABLE

FUNCTION	INPUTS						INTERNAL	OUTPUTS		
	СР	Di	Ē	CLR	POL	OE-W	OE-Y	Q	Wi	Yį
Output Three-State Control	×××	××××	××××	X X X	X X X	HLHL	L H H L	NC NC NC	Z Enabled Z Enabled	Enabled Z Z Enabled
W _i Polarity	×	X	×	X	L	L	L	NC NC	Non-Inverting Inverting	Non-Inverting Non-Inverting
Asynchronous Clear	×	×	×	L	L H	L	L	Ĺ	L H	L L
Clock Enabled	1 1 1	X L H	H	HHHH	XLHLH	X L L	X L L	NC L H	NC L H	NC L H H

L = LOW H = HIGH Z = High-Impedance

X = Don't Care
NC = No Change
t = LOW to HIGH Transition

APPLICATION



Convenient Register Content Monitor or Test Point

ABSOLUTE MAXIMUM RATINGS

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices	
Temperature	0°C to +70°C
Supply Voltage	. +4.75V to +5.25V
Military (M) Devices	
Temperature	55°C to +125°C
Supply Voltage	+4.5V to +5.5V
Operating ranges define those limits over ality of the device is guaranteed.	or which the function-

DC CHARACTERISTICS over operating range unless otherwise specified

Parameters	Description	Test Conditions (Note 2)		Min	Typ (Note 1)	Max	Units	
		V _{CC} = MIN V _{IN} = V _{IH} or V _{IL}		=-1.0mA	2.4	3.4		1,000
VOH	Output HIGH Voltage			OH = -2.6mA	2.4	3.4		Volts
			IOL = 4.0	mA			0.4	
V-	Output LOW Voltage	V _{CC} = MIN	IOL = 8.0	mA			0.45	Volts
VOL	Output LOFF Foliage	VIN = VIH or VIL	IOL = 12r	nA			0.5	
ViH	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs			2.0			Volts
· · · · · · · · · · · · · · · · · · ·	Guaranteed input logical LOW MIL					0.7	51 88 88	
V _{1L} Input LOW Level		voltage for all inputs. COM'L		COM'L	7.01187		0.8	Volts
Vi	Input Clamp Voltage	VCC = MIN, I _{IN} = -18mA					- 1.5	Volts
IIL.	Input LOW Current	VCC = MAX, VIN =).4V				-0.36	mA
hн	Input HIGH Current	VCC = MAX, VIN = 2	2.7V		K		20	μΑ
l ₁	Input HIGH Current	VCC = MAX, VIN =	7.0V	70.0			0.1	mA
-			V _O = 0.4V				-20	
loz	Off-State (High-Impedance) Output Current	V _{CC} = MAX	Vo = 2.4	V			20	μΑ
Isc	Output Short Circuit Current (Note 3)	V _{CC} = MAX			-15		-85	mA
	Power Supply Current	2015 1275203		MIL	-1100	24	36	
loc	(Note 4)	V _{CC} = MAX CO		COM'L		24	39	mA

Notes: 1. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.

2. For conditions shown as MIN or MAX, use the appropriate value specified under Operating Ranges for the applicable device type.

3. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.

4. Inputs grounded; outputs open.

SWITCHING CHARACTERISTICS ($T_A = +25$ °C, $V_{CC} = 5.0V$)

Parameters	Description		Test Conditions	Min	Тур	Max	Units
t _{PHL}					22	33	
tpHL	Clock to Yi		l i		20	30	ns
tpLH	Clock to Wi	10.7			24	36	
t _{PHL}	(Either Polarity)				24	36	ns
1 _{PHL}	Clear to Yi				29	43	ns
1 _{PLH}	Parest A 1999			HUID CO	25	37	ns
IPHL	Clear to Wi				30	45	
l _{PLH}	To I Meson Marie III			2000	23	34	
1PHL	Polarity to Wi		C _L = 15pF		25	37	ns
tpw	Clear		$R_L = 2.0k\Omega$	18			ns
P"		OW		15			ns
lpw	Clock Pulse Width H	IIGH		18			
ts	Data			15			ns
th	Data			5			ns
ts	Data Enable	2011 115.0		20			ns
th	Data Enable			0			ns
ts	Set-up Time, Clear Recovery (Inactive) to	clock		20	15		ns
tzH	STEPTS MERCHANIS M. MINE	259W	1		11	17	1200
tzL	Output Enable to W or Y				13	20	ns
tHZ	Output Enable to W or Y		C _L = 5.0pF		13	20	
tLZ			$R_L = 2.0k\Omega$,	11	17	ns
f _{max}	Maximum Clock Frequ	uency (Note 1)	$C_L = 15pF$ $R_L = 2.0k\Omega$	35	45		MHz

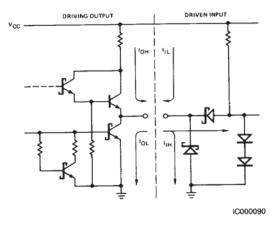
Note 1. Per industry convention, f_{max} is the worst case value of the maximum device operating frequency with no constraints on t_r, t_f, pulse width or duty cycle.

SWITCHING CHARACTERISTICS over operating range unless otherwise specified*

Parameters				COMM	ERCIAL	MILI	TARY	
	Description		Test Conditions	Am25	LS2519	Am25LS2519		
				Min	Max	Min	Max	Units
t _{PLH}					39		42]
1PHL	Clock to Yi			- Cths	39	- 10	45	ns
tplH	Clock to W				41	2500	43	ns
tpHL	(Either Pola	rity)		31%	44		48	ns
tpHL	Clear to Yi		1 [52		58	ns
tpLH	Clear to W _i			0.000	42		43	
tpHL				75 350	51	V	53	ns
tpLH					41		45	-
t _{PHL}			C _L ≈ 50pF		42		44	ns
t _{pw}	Clear		R _L = 2.0kΩ	20		20		ns
	PCV 33	LOW	1 [20		20		
tpw	Clock	HIGH	20		20		ns	
ts	Data			15		15		ns
th	Data			10		10		ns
ts	Data Enable	е	1 [25		25		ns
th	Data Enable	в		0		0	SHIPPE	ns
ts	Set-up Time Recovery (I	e, Clear (nactive) to Clock	1 [23		24		ns
tzH		TOTAL PROPERTY AND A STREET OF THE STREET OF	7 1		24		27	
tzı	Output Enable to Wi or Yi				29		35	
tHZ	Output Enable to W _i or Y _i		Ci = 5.0pF		33		45	ns
1LZ			$C_L = 5.0 pF$ $R_L = 2.0 k\Omega$	-16	22		26	115
f _{max}	Maximum Clock Frequency (Note 1)		$C_L = 5.0 pF$ $R_L = 2.0 k\Omega$	30		25		MHz

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

Am25LS2519 LOW-POWER SCHOTTKY INPUT/OUTPUT CURRENT INTERFACE CONDITIONS



Note: Actual current flow direction shown.